



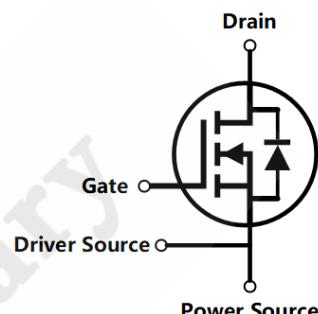
# P3M06060K4 SiC MOS N-Channel Enhancement Mode

$V_{RRM}$	=	650	V
$I_D$	=	48	A
$I_D(100^\circ\text{C})$	=	34	A
$R_{DS(on)}$	=	60	mΩ

## SiC MOS P3M06060K4 N-Channel Enhancement Mode

### Features

- Qualified to AEC-Q101
- High Blocking Voltage with Low On-Resistance
- High-Frequency Operation
- Ultra-Small  $Q_{gd}$
- 100% UIS tested



### Standards Benefits

- Improve System Efficiency
- Increase Power Density
- Reduce Heat Sink Requirements
- Reduction of System Cost

TO-247-4

Drain	1
Power Source	2
Driver Source	3
Gate	4

### Applications

- Solar Inverters
- EV Battery Chargers
- High Voltage DC/DC Converters
- Switch Mode Power Supplies



### Order Information

Part Number	Package	Marking
P3M06060K4	TO-247-4	P3M06060K4



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## 1. Maximum Ratings

At  $T_J = 25^\circ\text{C}$ , unless specified otherwise

Parameter	Symbol	Value	Unit	Test Conditions
Drain - Source Voltage	$V_{DS\max}$	650	V	$V_{GS} = -3\text{V}$ $I_D = 100\mu\text{A}$
Gate - Source Voltage (dynamic)	$V_{GS\max}$	-8 / +20	V	AC ( $f > 1 \text{ Hz}$ )
Gate - Source Voltage (static)	$V_{GSop}$	-3 / +15	V	Static
Continuous Drain Current	$I_D$	48	A	$V_{GS} = 15\text{V}$ $T_C = 25^\circ\text{C}$
		34		$V_{GS} = 15\text{V}$ $T_C = 100^\circ\text{C}$
Power Dissipation	$P_D$	188	W	
Operating Junction	$T_J$	-55 To +175	$^\circ\text{C}$	
Storage Temperature	$T_{stg}$	-55 To +175	$^\circ\text{C}$	
Solder Temperature	$T_L$	260	$^\circ\text{C}$	
Mounting Torque	$M_d$	1 8.8	Nm lbf-in	M3 or 6-32 screw



## 2. Electrical Characteristics

At  $T_J = 25^\circ\text{C}$ , unless specified otherwise

Parameter	Symbol	Value			Unit	Test Conditions
		Min.	Typ.	Max.		
Drain-Source Breakdown Voltage	$V_{(\text{BR})\text{DSS}}$	650	/	/	V	$V_{GS} = -3\text{V}$ $I_D = 100\mu\text{A}$
Gate Threshold Voltage	$V_{GS(\text{th})}$	1.8	2.2	/	V	$V_{DS} = V_{GS}$ $I_D = 20\text{mA}$ $T_J = 25^\circ\text{C}$
		/	1.65	/	V	$V_{DS} = V_{GS}$ $I_D = 20\text{mA}$ $T_J = 175^\circ\text{C}$
Reverse Bias Drain Current	$I_{DSS}$	/	0.5	10	$\mu\text{A}$	$V_{GS} = -3\text{V}$ $V_{DS} = 650\text{V}$
Gate-Source Leakage Current	$I_{GSS}$	/	20	250	nA	$V_{GS} = 15\text{V}$ $V_{DS} = 0\text{V}$
Drain-Source On-State Resistance	$R_{DS(\text{on})}$	/	60	79	$\text{m}\Omega$	$V_{GS} = 15\text{V}$ $I_D = 20\text{A}$
		/	52	/	$\text{m}\Omega$	$V_{GS} = 18\text{V}$ $I_D = 20\text{A}$
Trans conductance	$g_{fs}$	/	12	/	S	$V_{DS} = 20\text{V}$ $I_{DS} = 20\text{A}$ $T_J = 25^\circ\text{C}$
		/	11	/	S	$V_{DS} = 20\text{V}$ $I_{DS} = 20\text{A}$ $T_J = 175^\circ\text{C}$
Input Capacitance	$C_{iss}$	/	1911	/	pF	$V_{GS} = 0\text{V}$ $V_{DS} = 400\text{V}$ $f = 1\text{MHz}$ $V_{AC} = 25\text{mV}$
Output Capacitance	$C_{oss}$	/	162	/	pF	
Reverse Transfer Capacitance	$C_{rss}$	/	15.3	/	pF	
Coss Stored Energy	$E_{oss}$	/	15	/	$\mu\text{J}$	



# P3M06060K4 SiC MOS

## N-Channel Enhancement Mode

Parameter	Symbol	Value			Unit	Test Conditions
		Min.	Typ.	Max.		
Turn-on Energy	$E_{on}$	/	51	/	$\mu$	$V_{DS} = 400V$ $V_{GS} = -3/15V$ $I_D = 20A$ $R_G = 1\Omega$
Turn-off Energy	$E_{off}$	/	32	/		
Turn-On Delay Time	$T_{d(on)}$	/	14	/		
Rise Time	$T_r$	/	13	/		
Turn-Off Delay Time	$T_{d(off)}$	/	22	/		
Fall Time	$T_f$	/	17	/		
Internal Gate Resistance	$R_{G(int)}$	/	1.06	/		
Gate to Source Charge	$Q_{gs}$	/	17.5	/		$V_{DS} = 400V$ $I_{DS} = 20A$ $V_{GS} = -3 \text{ to } 15V$ $I_G = 50mA$
Gate to Drain Charge	$Q_{gd}$	/	15.3	/		
Total Gate Charge	$Q_g$	/	53.1	/		

### 3. Reverse Diode Characteristics

At  $T_J = 25^\circ C$ , unless specified otherwise

Parameter	Symbol	Value		Unit	Test Conditions
		Typ.	Max.		
Diode Forward Voltage	$V_{SD}$	4.8	/	V	$V_{GS} = -3V$ $I_{SD} = 10A$ $T_J = 25^\circ C$
		4.3	/		
Continuous Diode Forward Current	$I_S$	29	/	A	$V_{GS} = -3V$



# P3M06060K4 SiC MOS N-Channel Enhancement Mode

Reverse Recover Time	$t_{rr}$	18	/	ns	$V_{GS} = -3/15V$
Reverse Recovery Charge	$Q_{rr}$	473	/	nC	$I_{SD} = 20A$ $V_R = 400V$ $d_i/d_t = 3700A/\mu s$
Peak Reverse Recovery Current	$I_{rrm}$	44	/	A	$T_J = 25^{\circ}C$

## 4. Thermal Characteristics

Parameter	Symbol	Value	Unit
Thermal Resistance from Junction to Case	$R_{\theta JC}$	0.8	°C/W

## 5. Typical Performance

At  $T_J = 25^{\circ}C$ , unless specified otherwise

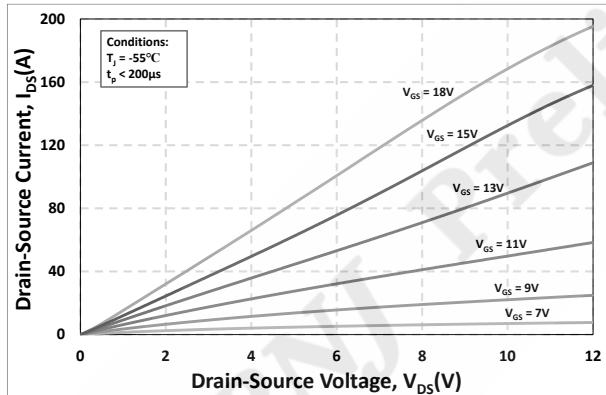


Figure 1. Output Characteristics  $T_J = -55^{\circ}C$

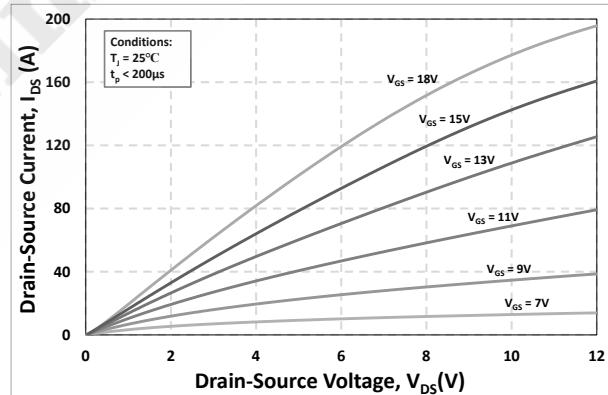


Figure 2. Output Characteristics  $T_J = 25^{\circ}C$

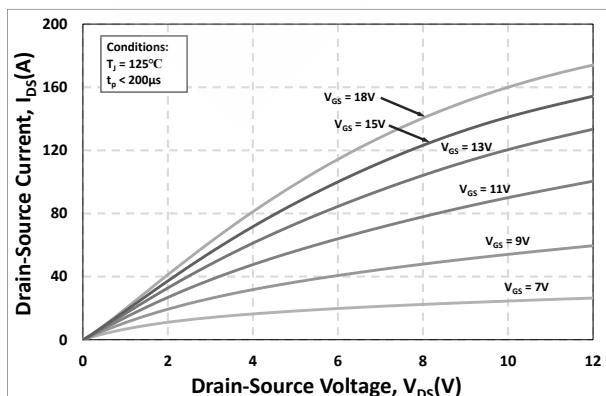


Figure 3. Output Characteristics  $T_J = 125^{\circ}C$

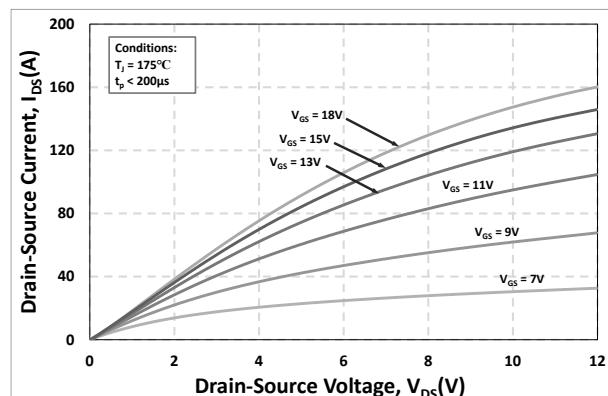


Figure 4. Output Characteristics  $T_J = 175^{\circ}C$



# P3M06060K4 SiC MOS N-Channel Enhancement Mode

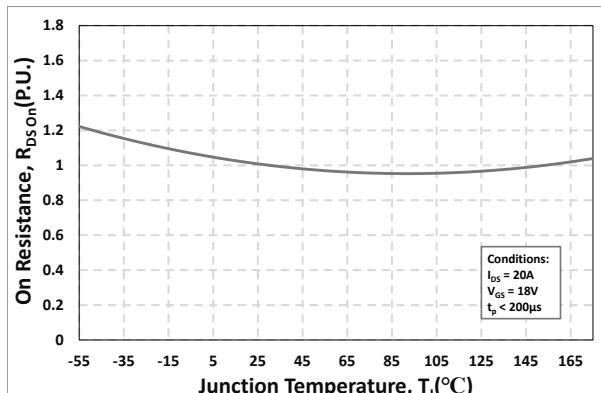


Figure 5. Normalized On-Resistance vs. Temperature

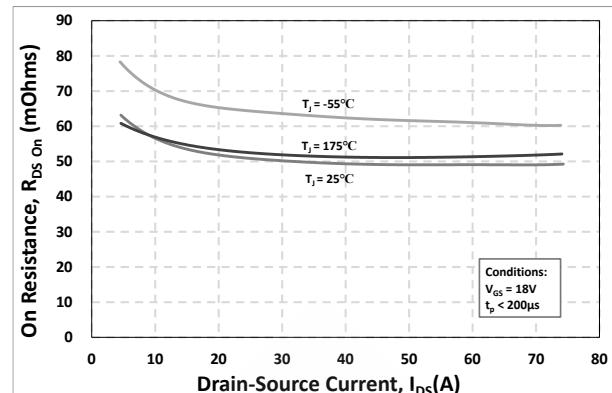


Figure 6. On-Resistance vs. Drain Current Various Temperatures

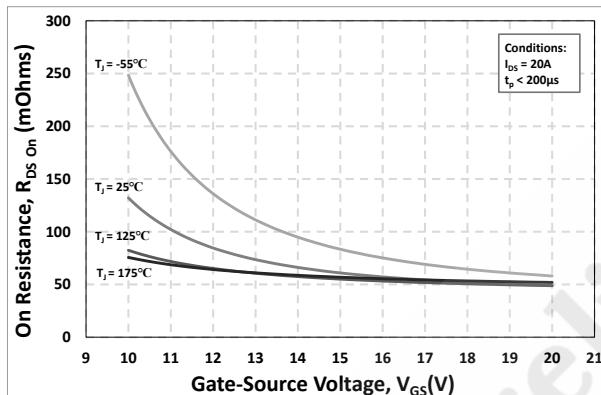


Figure 7. On-Resistance vs. Gate-Source Voltage

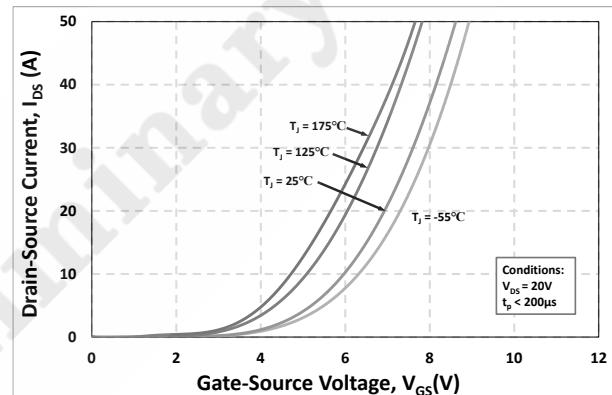


Figure 8. Transfer Characteristic for Various Junction Temperatures

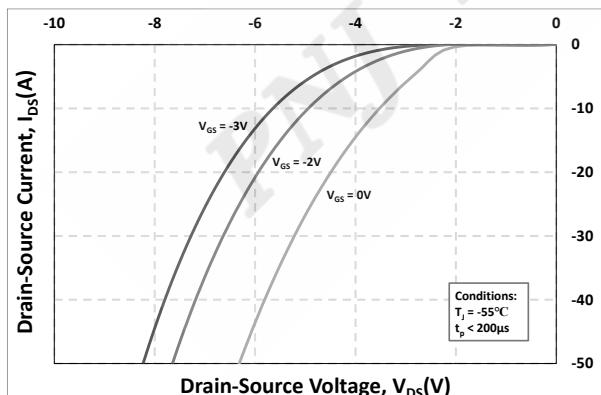


Figure 9. Body Diode Characteristic at -55°C

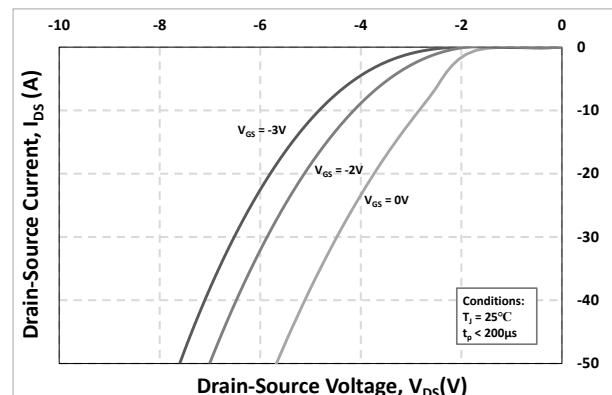
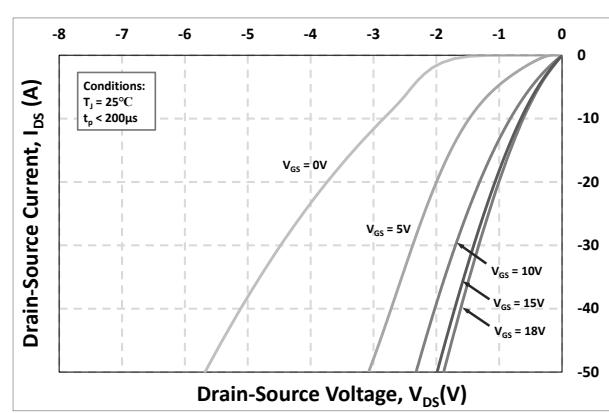
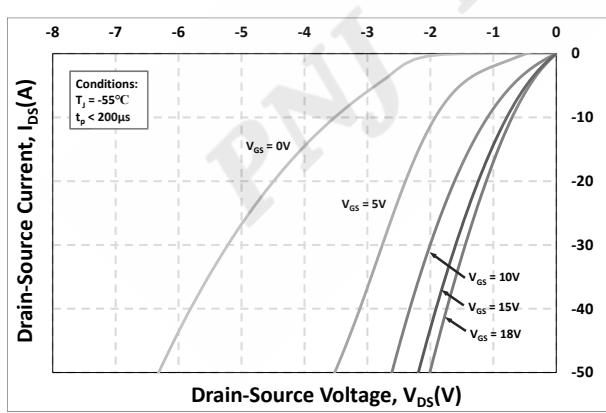
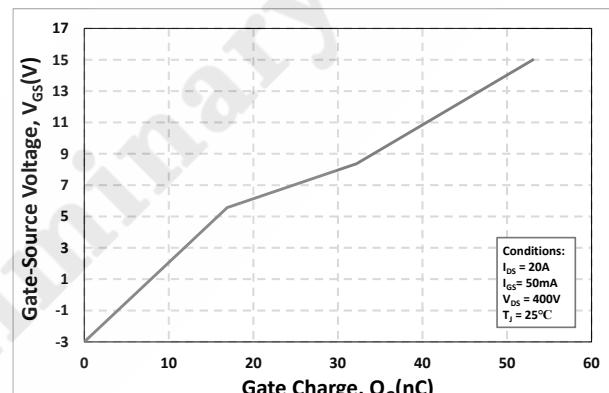
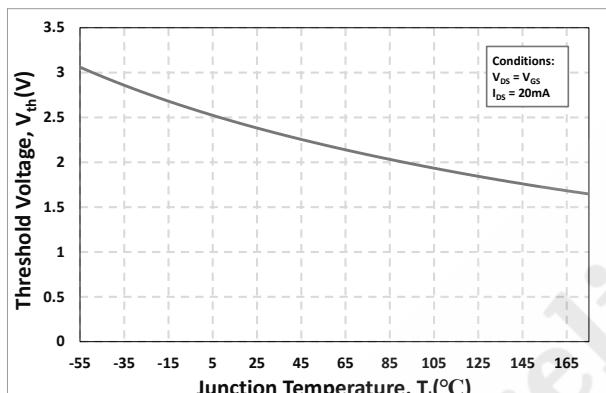
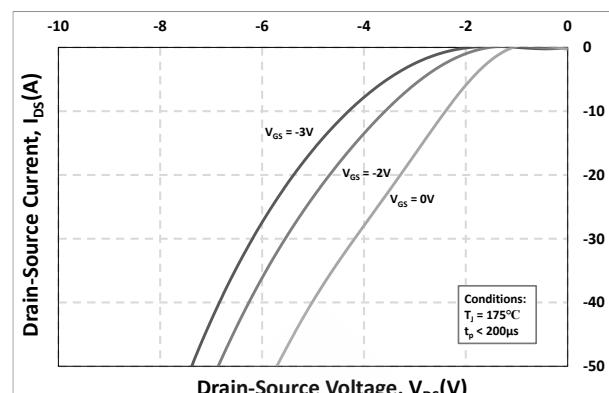
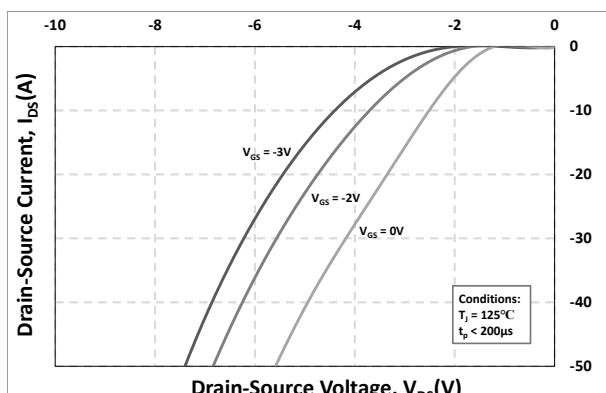


Figure 10. Body Diode Characteristic at 25°C



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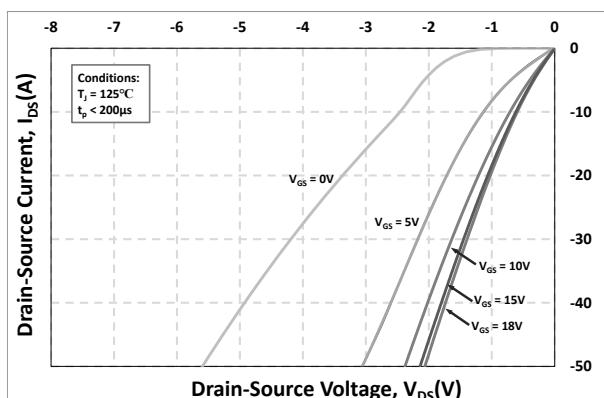


Figure 17. 3rd Quadrant Characteristic at 125°C

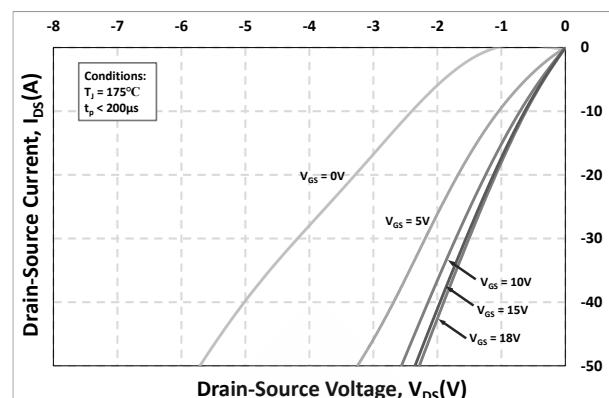


Figure 18. 3rd Quadrant Characteristic at 175°C

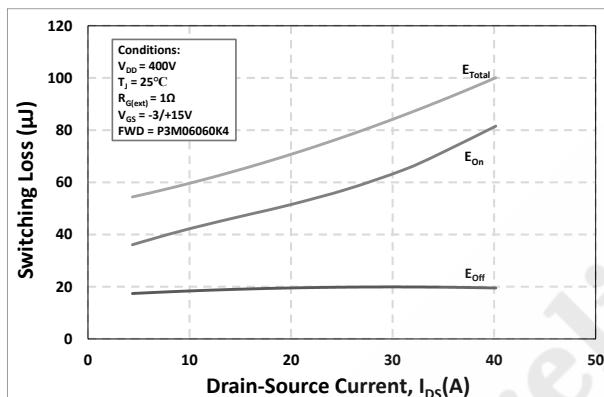


Figure 19. Clamped Inductive Switching Energy vs.  
Drain Current ( $V_{DD} = 400V$ )

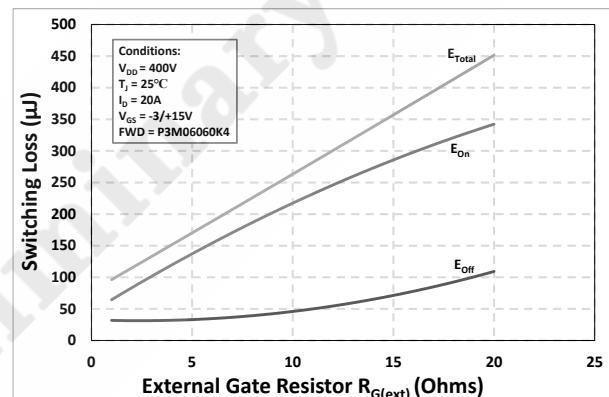


Figure 20. Clamped Inductive Switching Energy vs.  
 $R_{G(ext)}$

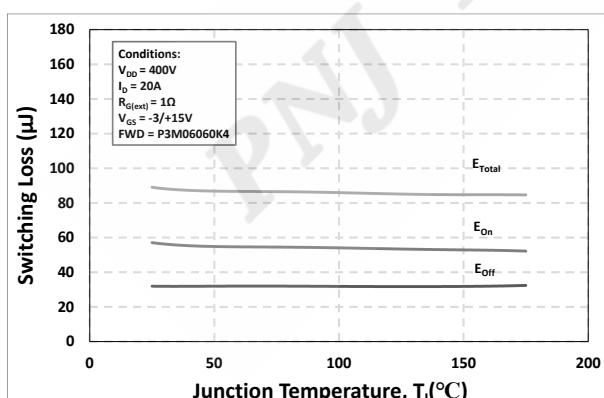


Figure 21. Clamped Inductive Switching Energy vs.  
Temperature

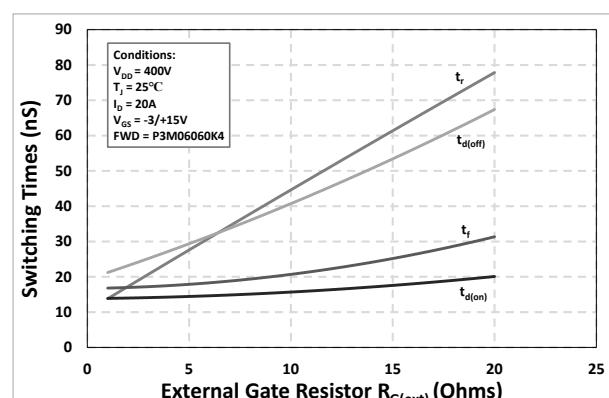


Figure 22. Switching Times vs.  $R_{G(ext)}$



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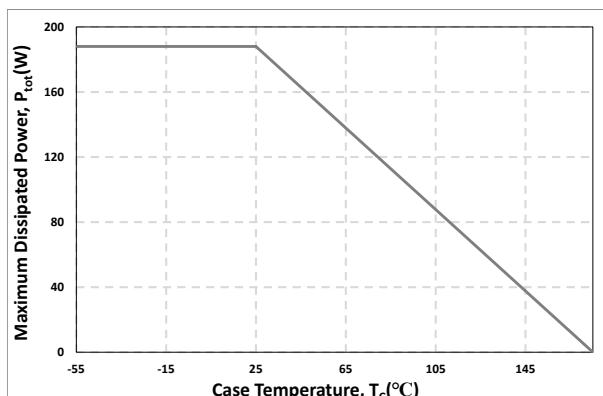


Figure 23. Maximum Power Dissipation Derating vs. Case Temperature

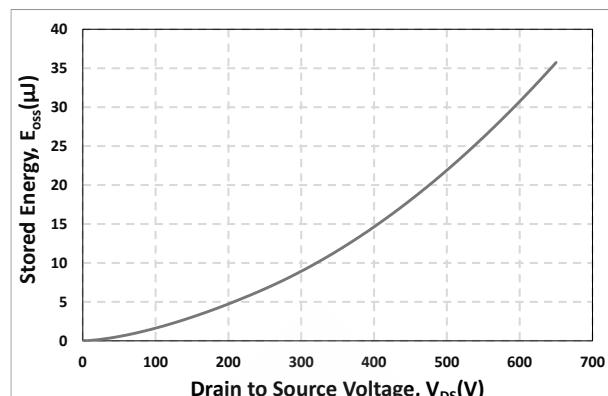


Figure 24. Output Capacitor Stored Energy

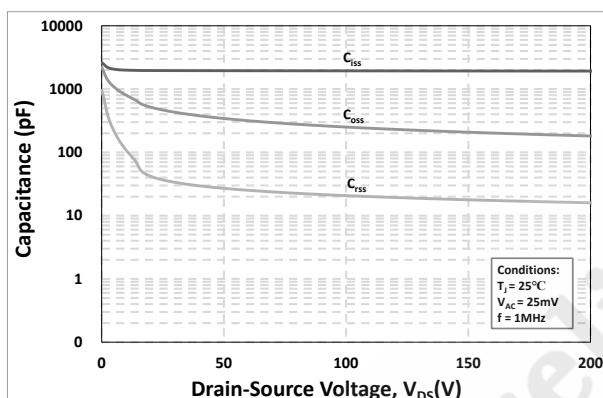


Figure 25. Capacitances vs. Drain-Source Voltage (0 - 200V)

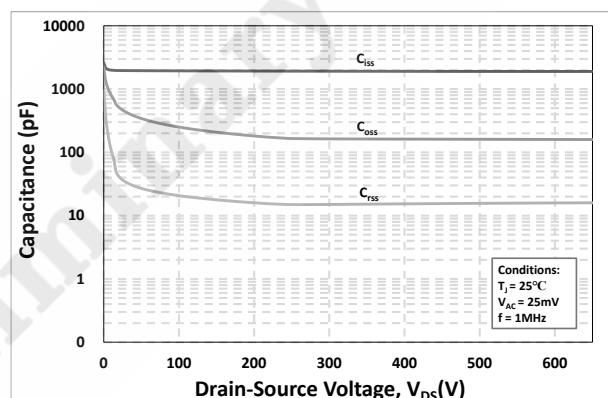


Figure 26. Capacitances vs. Drain-Source Voltage (0 - 650V)

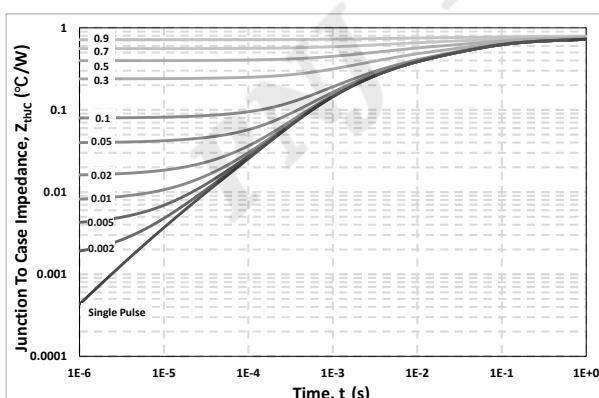


Figure 27. Transient Thermal Impedance (Junction - Case)

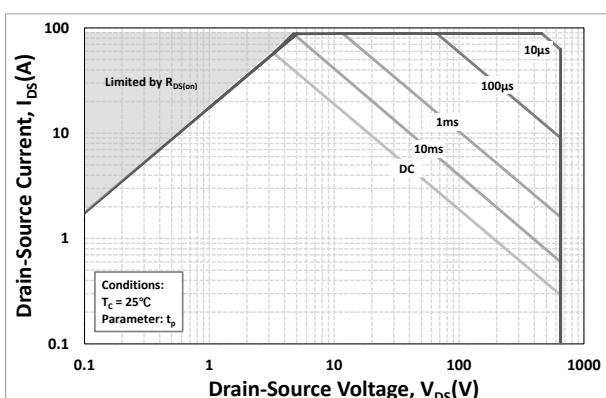
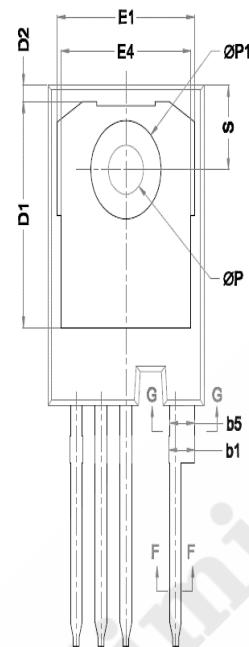
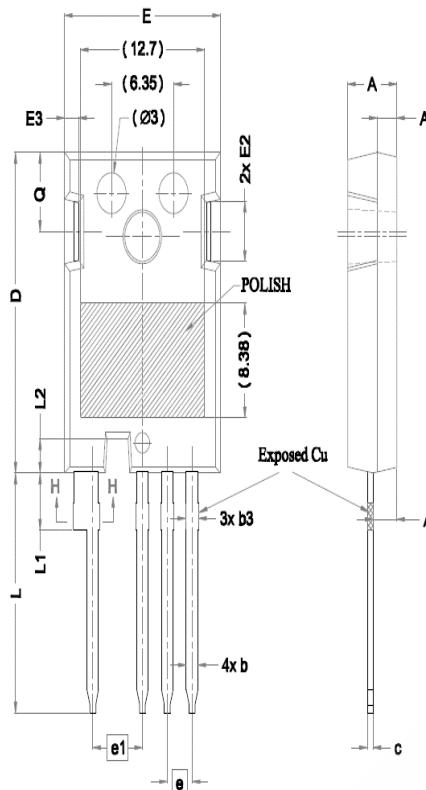


Figure 28. Safe Operating Area



## 6. Package Outlines



Symbol	Dimensions		
	M in.	Nom.	Max.
A	4.83	5.02	5.21
A1	2.28	2.41	2.54
A2	1.91	2.00	2.16
b <sup>1</sup>	1.07	1.20	1.28
b	1.07	1.20	1.33
b1	2.39	2.67	2.94
b2	2.39	2.67	2.84
b3	1.07	1.30	1.60
b4	1.07	1.30	1.50
b5	2.39	2.53	2.69
b6	2.39	2.53	2.64
c	0.55	0.60	0.68
c1	0.55	0.60	0.65
D	22.30	23.45	23.80
D1	16.25	16.55	17.65
D2	0.95	1.19	1.25
E	15.75	15.94	16.13
E1	13.10	14.02	14.15
E2	3.60	1.10	5.10
E3	1.00	1.45	1.90
E4	12.38	13.26	13.43
e	2.54BSC		
e1	5.08BSC		
L	17.31	17.57	17.82
L1	3.97	4.19	4.37
L2	2.35	2.50	2.65
ØP	3.51	3.61	3.65
ØP	7.19 REF.		
Q	5.49	5.79	6.00
S	6.04	6.17	6.30

Drawing and Dimensions